

Supplementary Information for:

Crystal Structure Manipulation of the Exchange Bias in an Antiferromagnetic Film

Wei Yuan^{1,2}, Tang Su^{1,2}, Qi Song^{1,2}, Wenyu Xing^{1,2}, Yangyang Chen^{1,2}, Tianyu Wang^{1,2},
Zhangyuan Zhang^{3,4}, Xiumei Ma³, Peng Gao^{2,3}, Jing Shi^{5*}, and Wei Han^{1,2*}

¹International Center for Quantum Materials, Peking University, Beijing, 100871, P. R. China

²Collaborative Innovation Center of Quantum Matter, Beijing 100871, P. R. China

³Electron Microscopy Laboratory, School of Physics, Peking University, Beijing, 100871, P. R. China

⁴Department of Physics and Key Laboratory of Artificial Micro- and Nano-structures of Ministry of Education, Wuhan University, Wuhan 430072, P. R. China

⁵Department of Physics and Astronomy, University of California, Riverside, California 92521, USA

*Correspondence to be addressed to: jing.shi@ucr.edu (J.S.) and weihan@pku.edu.cn (W.H.)

Figure S1

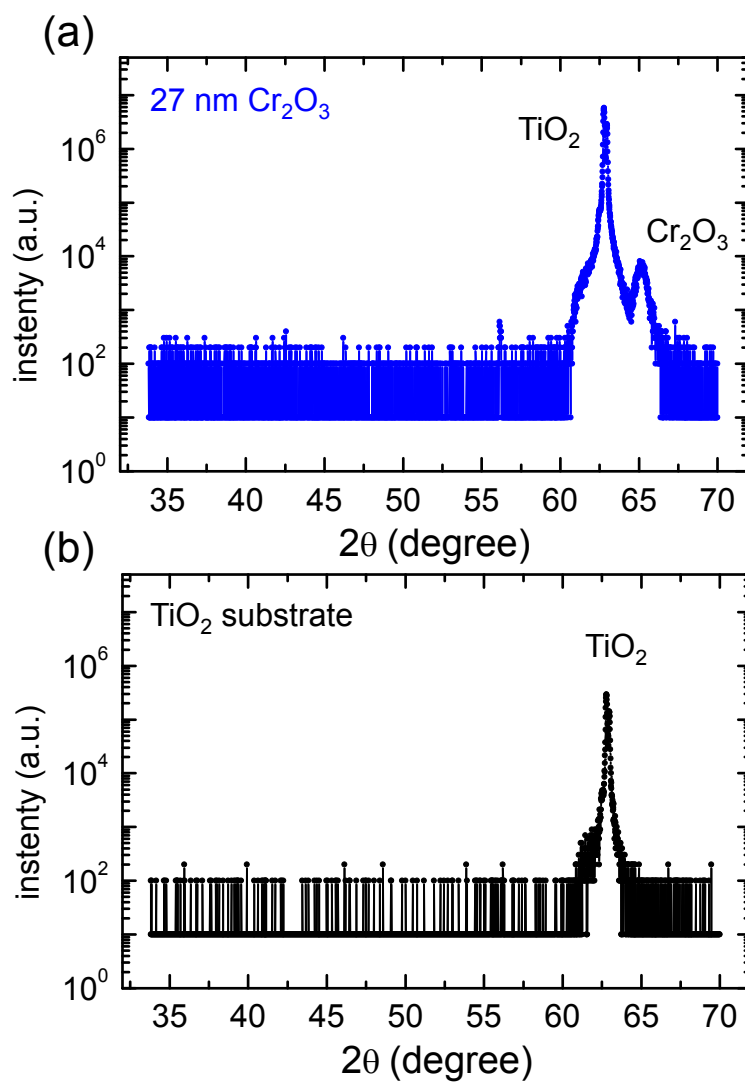


Fig. S1. The theta-2theta X-ray diffraction scans for 27 nm Cr_2O_3 films (a) and the rutile TiO_2 substrate (b), respectively.